

RFP22N10, RF1S22N10SM

Data Sheet

January 2002 File Number 2385.3

22A, 100V, 0.080 Ohm, N-Channel Power MOSFETs

These N-Channel power MOSFETs are manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use in applications such as switching regulators, switching converters, motor drivers, and relay drivers. These transistors can be operated directly from integrated circuits.

Formerly developmental type TA9845.

Ordering Information

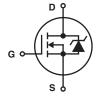
PART NUMBER	PACKAGE	BRAND
RFP22N10	TO-220AB	RFP22N10
RF1S22N10SM	TO-263AB	F1S22N10

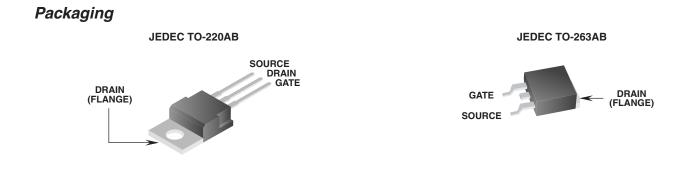
NOTE: When ordering use the entire part number. Add the suffix, 9A, to obtain the TO-263AB variant in tape and reel, e.g. RF1S22N10SM9A.

Features

- 22A, 100V
- $r_{DS(ON)} = 0.080\Omega$
- UIS SOA Rating Curve (Single Pulse)
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- 175°C Operating Temperature
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol





Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	RFP22N10, RF1S22N10SMS	UNITS
Drain to Source Voltage (Note 1)V _{DSS}	100	V
Drain to Gate Voltage (R _{GS} = 1MΩ) (Note 1)V _{DGR}	100	V
Gate to Source Voltage	±20	V
Continuous Drain CurrentI _D Pulsed Drain CurrentI _{DM}	22 50	A A
Maximum Power Dissipation	100	W
Linear Derating Factor	0.67	W/ ^o C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10s	300 260	°C Oo

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $150^{\circ}C$.

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	ТҮР	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	$I_D = 250\mu A, V_{GS} = 0$ (Figure 7)		100	-	-	V
Gate to Source Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$, $I_D = 250\mu A$ (Figure 9)		2	-	4	V
Zero-Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 80V, V_{GS} = 0V$		-	-	1	μΑ
		$V_{DS} = 80V, V_{GS} = 0V, T_{C} = 150^{\circ}C$		-	-	50	μΑ
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0$		-	-	±100	nA
Drain to Source On Resistance (Note 2)	rDS(ON)	I _D = 22A, V _{GS} = 10V (Figure 8)		-	-	0.080	Ω
Turn-On Time	t _(ON)	$V_{DD} = 50Vwwwwwww, I_D = 11A, R_L = 4.5\Omega, V_{GS} = 10V, R_{GS} = 25\Omega$ (Figure 11)		-	-	60	ns
Turn-On Delay Time	t _{d(ON)}			-	13	-	ns
Rise Time	t _r			-	24	-	ns
Turn-Off Delay Time	t _{d(OFF)}			-	65	-	ns
Fall Time	t _f			-	18	-	ns
Turn-Off Time	t _(OFF)			-	-	120	ns
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 0V$ to 20V	$V_{DD} = 80V, I_D \approx 22A,$ $R_L = 3.64\Omega$ $I_g(REF) = 1mA$	-	-	150	nC
Gate Charge at 10V	Q _{G(10)}	$V_{GS} = 0V$ to 10V		-	-	75	nC
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 0V$ to 2V	(Figure 11)	-	-	3.5	nC
Thermal Resistance Junction to Case	R _{θJC}			-	-	1.5	°C/W
Thermal Resistance Junction to Ambient	R _{0JA}	TO-220 and TO-263		_	-	62	°C/W

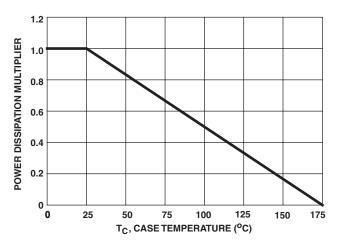
Source to Drain Diode Specifications

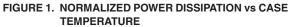
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	ТҮР	MAX	UNITS
Source to Drain Diode Voltage (Note 2)	V _{SD}	I _{SD} = 22A	-	-	1.5	V
Diode Reverse Recovery Time	t _{rr}	$I_{SD} = 22A$, $dI_{SD}/dt = 100A/\mu s$	-	-	200	ns

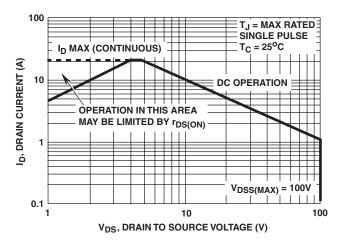
NOTE:

2. Pulse Test: Pulse Duration = 300μ s maximum, duty cycle = 2%.

Typical Performance Curves Unless otherwise Specified









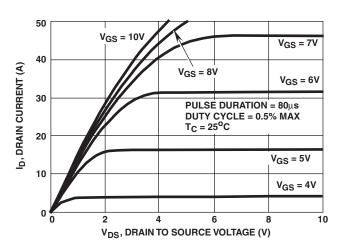


FIGURE 5. SATURATION CHARACTERISTICS

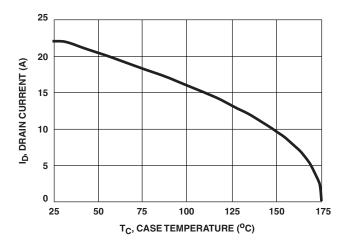


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

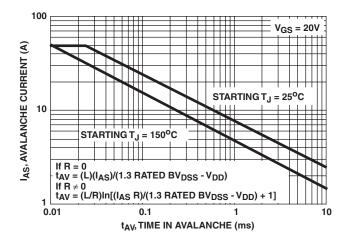


FIGURE 4. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

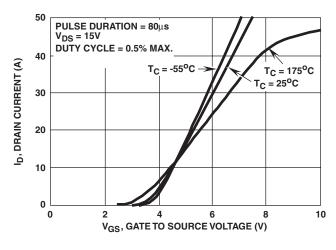
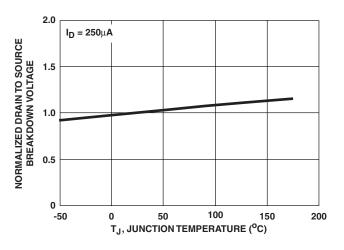


FIGURE 6. TRANSER CHARACTERISTICS

Typical Performance Curves Unless otherwise Specified (Continued)





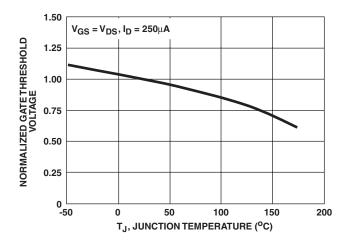


FIGURE 9. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

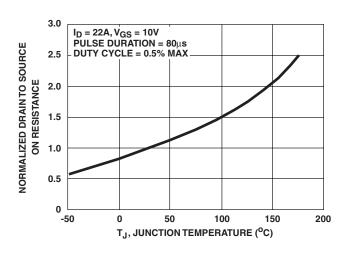


FIGURE 8. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

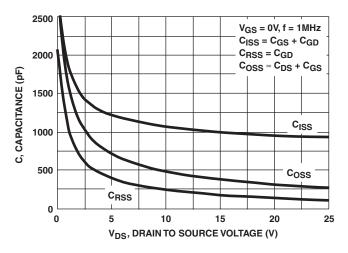


FIGURE 10. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

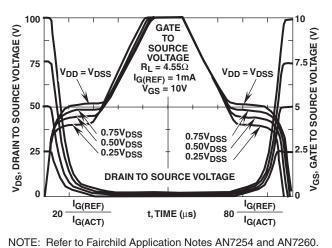


FIGURE 11. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

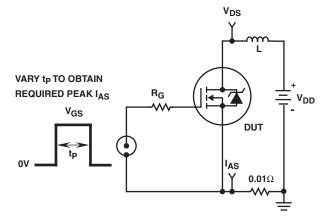


FIGURE 12. UNCLAMPED ENERGY TEST CIRCUIT

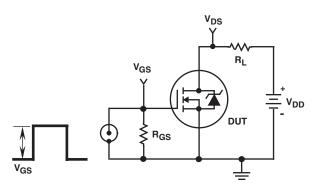


FIGURE 14. SWITCHING TIME TEST CIRCUIT

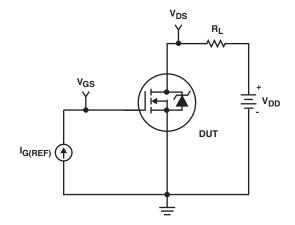


FIGURE 16. GATE CHARGE TEST CIRCUIT

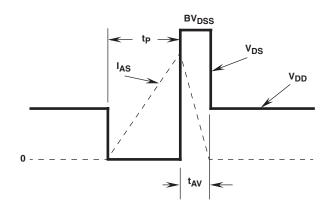
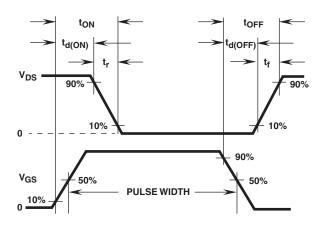
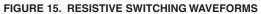


FIGURE 13. UNCLAMPED ENERGY WAVEFORMS





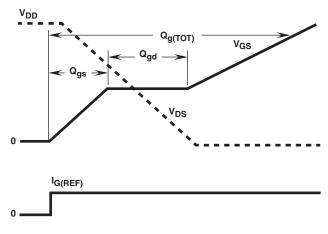


FIGURE 17. GATE CHARGE WAVEFORMS

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™ Bottomless™ CoolFET™ CROSSVOLT™ DenseTrench™ DOME™ **EcoSPARK™** E²CMOS[™] EnSigna™ FACT™ FACT Quiet Series™ FAST ® FASTr™ FRFET™ GlobalOptoisolator[™] POP[™] GTO™ HiSeC™ ISOPLANAR™ LittleFET™ MicroFET™ MicroPak™ MICROWIRE™

OPTOLOGIC™ OPTOPLANAR™ PACMAN™ Power247™ PowerTrench[®] QFET™ QS™ QT Optoelectronics[™] Quiet Series[™] SILENT SWITCHER®

SMART START™ VCX™ STAR*POWER™ Stealth™ SuperSOT[™]-3 SuperSOT[™]-6 SuperSOT[™]-8 SyncFET™ TinyLogic™ TruTranslation[™] UHC™ UltraFET[®]

STAR*POWER is used under license

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY. FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.
	In Design First Production Full Production